

S **Nitrogen isotope analysis of NaNO₃ and KNO₃ by nano secondary ion mass spectrometry using the ¹⁵N¹⁶O₂⁻/¹⁴N¹⁶O₂⁻ ratio**

Kexue Li, Baerbel Sinha and Peter Hoppe
J. Vac. Sci. Technol. B **34**, 030601 (2016);
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Aaron B. Clubb, Michael J. Eller, Stanislav V. Verkhoturov, Emile A. Schweikert, Rachel M. Anderson and Richard M. Crooks

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Joshua S. Wallace, Austin Quinn, Joseph A. Gardella Jr., Jing Hu, Eric Siu-Wai Kong and Han-Ik Joh
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Computer modeling of angular emission from Ag(100) and Mo(100) surfaces due to Ar_n cluster bombardment

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Secondary ions produced by electrospray droplet impact with *m/z* selection from 10³ to 10⁶

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